ABSTRACT OF THE DISCLOSURE

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2   According to one embodiment, a programmable logic assembly (**200**) may include a

3 nonvolatile memory (**202**) may be coupled to an associated volatile programmable logic

4 device (PLD) (**204**). Built-in-self-test (BIST) data (**208**) may be stored in a nonvolatile

5 memory (**202**) that places the volatile PLD (**204**) in a self-test configuration. If a volatile

6 PLD (**204**) passes a self-test, user data (**210**) may be stored in a nonvolatile memory (**202**)

7 that places a volatile PLD (**204**) into a user determined configuration.

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